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Technical Compliance

No. ACS-E17354

The following product has been tested by us with the listed standards and found in compliance with the council EMC directive 2014/30/EU. It is demonstrative for the compliance with this EMC Directive.

Applicant

TPV Electronics (FuJian) Co., Ltd.

Rongqiao Economic and Technological Development Zone,

Fuqing City, Fujian Province, P.R. China

Product

LCD Monitor

Model No.

PD-55* (*=A-Z, a-z, 0-9, hyphen, \ or blank)

Serial No.

N/A

Brand

AG neovo

| | Test Standards: | |
|---|---|---------------------------------------|
| EN 55032: 2012+AC:2013 (Class A) CISPR 32: 2012 (AS/NZS CISPR 32: 2015) | Electromagnetic compatibility of multimedia equipment - Emission requirements | |
| EN 61000-3-2: 2014 | Electromagnetic compatibility(EMC) Part 3-2:Limits-Limits for harmonic current emissions(equipment input current ≤ 16A per phase) | |
| EN 61000-3-3: 2013 | Electromagnetic compatibility(EMC) Part 3-3:Limits-Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current ≤16A per phase and not subject to conditional connection | |
| EN 55024: 2010 EN 55024: 2010+A1:2015 | Information technology equipment-Immunity characteristics limits and methods of measurement | |
| | IEC 61000-4-2: 2008 | Electrostatic Discharge |
| | IEC 61000-4-3: 2010 | RF Field Strength Susceptibility |
| | IEC 61000-4-4: 2012 | Electrical Fast Transients |
| | IEC 61000-4-5: 2014 | Surge |
| | IEC 61000-4-6: 2013 | Conducted Susceptibility |
| | IEC 61000-4-8: 2009 | Magnetic Field Immunity |
| | IEC 61000-4-11: 2004 | Dips / Voltage Interruption Variation |

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信章科技 (深圳) 有限公司

Audix Technology (Shenzhen) Co., Ltd.

EMC部門報告専用章

Stamp only for EMC Dept. Report

Signature:

David Jin Manager

Date: May.24,2017

The technical compliance is based on a single evaluation of one sample of above mentioned product. It does not imply an assessment of the whole production and does not permit the use of the test lab. logo.